

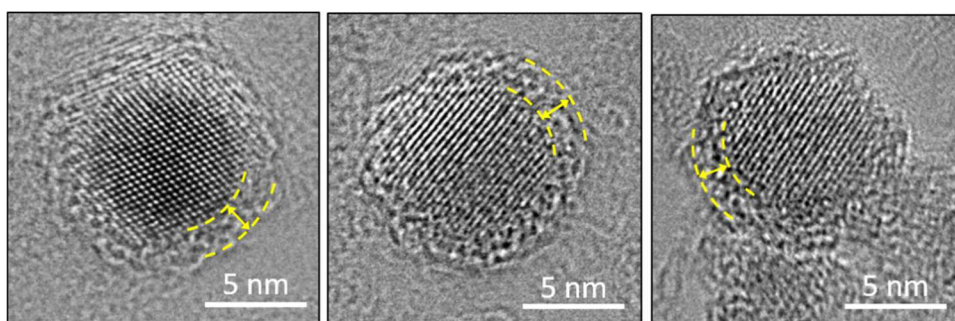
Supporting Information for

## Visualizing core-shell structure of heavily doped silicon quantum dots by electron microscope using atomically thin support film

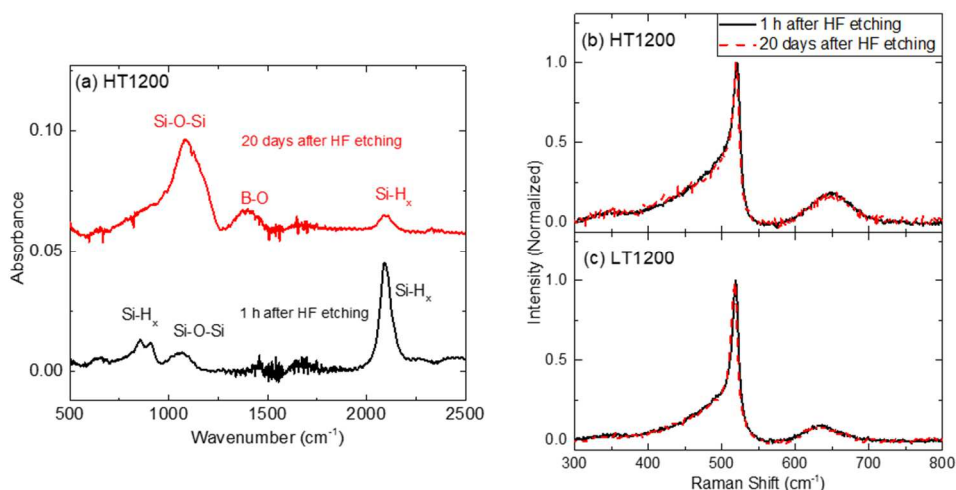
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**Figure S1.** Representative HRTEM images of Si QDs in HT1200 after ion cleaning process.



**Figure S2.** (a) IR absorption spectra of HT1200 1h (black) and 20 days (red) after HF etching. (d) Raman scattering spectra of (b) HT1200 and (c) LT1200 1h (black solid curves) and 20 days (red dashed curves) after HF etching.